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**Groupe de travail sur la révision de la CIB**

**Cinquante-et-unième session**

**Genève, 15 – 19 avril 2024**

**Special Union for the International Patent Classification**

**(IPC Union)**

**IPC Revision Working Group**

**Fifty-First Session**

**Geneva, April 15 to 19, 2024**

**LISTE PROVISOIRE[[1]](#footnote-2)\* DES PARTICIPANTS/**

**PROVISIONAL LIST[[2]](#footnote-3)\* OF PARTICIPANTS**

*établie par le Secrétariat/*

*prepared by the Secretariat*

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1. \* Les participants sont priés d’informer le Secrétariat, en modifiant la présente liste provisoire, des modifications qui devraient être prises en considération lors de l’établissement de la liste finale des participants. [↑](#footnote-ref-2)
2. \* Participants are requested to inform the Secretariat of any changes which should be taken into account in preparing the final list of participants. Changes should be requested by making corrections on the present provisional list. [↑](#footnote-ref-3)